



VSP-MIKRON



Soft Fast Recovery Diode

Preliminary Specification, Rev 1, oct. 2013

$V_{RRM} = 1200V$

$I_F = 1A$

Die Size:

1.62 x 1.62mm

KD01120F

Ultra low losses

Passivation: Silicon Oxide

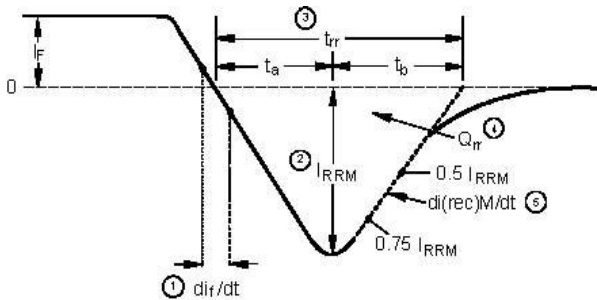
Maximum rated values:

Parameter	Symbol	min	max	Unit
Repetitive peak reverse voltage	V_{RRM}	-	1200	V
Continuous forward current	I_F	-	1	A
Repetitive peak forward current*	I_{FRM}	-	2	A
Junction temperature	T_{vj}	-	150	°C

* - Limited by $T_{vj,max}$

Diode Characteristics values:

Parameter	Symbol	Conditions	min	typ	max	Unit
Continuous forward voltage	V_F	$I_F = 1A, T_{vj} = 25^\circ C$		1.5	1.7	V
Continuous reverse current	I_R	$V_R = 1200V, \frac{T_{vj} = 25^\circ C}{T_{vj} = 125^\circ C}$		0.8	10 0.5	μA mA
Peak reverse recovery current	I_{RRM}	$I_F = 1A, V_R = 700V,$ $di_F/dt = 200A/\mu S,$ $T_{vj} = 25^\circ C$		tdb		A
Recovered charge	Q_{rr}			tdb		μC
Reverse Recovery Time	t_{rr}			tdb		nS
Reverse Recovery Time	t_{rr}	$I_F = 1A, V_R = 30V,$ $di_F/dt = 200A/\mu S.$		150	150	nS

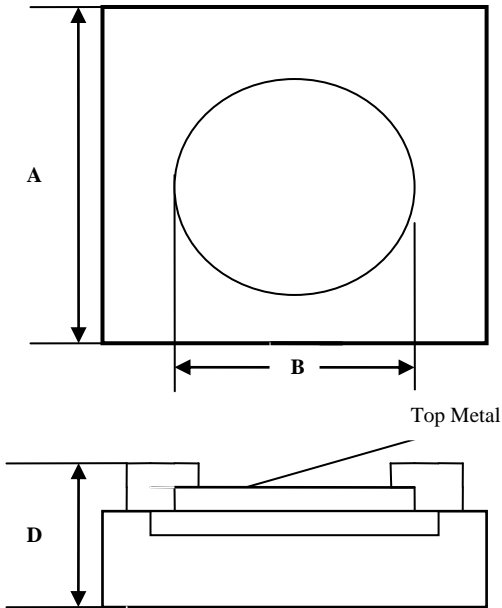


- di/dt - Rate of change of current through zero crossing
- I_{RRM} - Peak reverse recovery current
- t_{rr} - Reverse recovery time measured from zero crossing point of negative going I_F to point where a line passing through $0.75 I_{RRM}$ and $0.50 I_{RRM}$ extrapolated to zero current
- Q_{rr} - Area under curve defined by t_{rr} and I_{RRM}
$$Q_{rr} = \frac{t_{rr} \times I_{RRM}}{2}$$
- $di_{(rec)}/dt$ - Peak rate of change of current during t_b portion of t_{rr}

Mechanical properties:

Top metal: **Al** – for Wire Bonding

Backside metal: **Ti-Ni-Ag** – for Soldering



DIM	ITEM	μm
A _x A _y	Die Size	1620 1620
B _x B _y	Top Metal Size (d)	660
D	Thickness	350max.
Scribe line Width		50